



May 2006  
**FRFET™**

# FQP13N50CF / FQPF13N50CF 500V N-Channel MOSFET

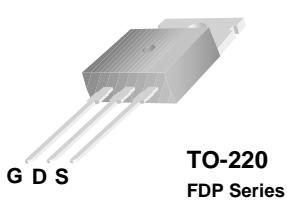
## Features

- 13A, 500V,  $R_{DS(on)} = 0.54\Omega$  @  $V_{GS} = 10\text{ V}$
- Low gate charge (typical 43 nC)
- Low  $C_{rss}$  (typical 20pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- Fast recovery body diode (typical 100ns)

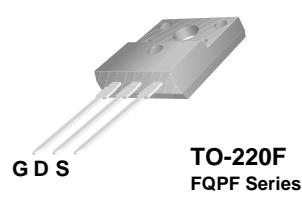
## Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

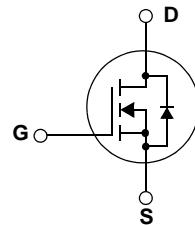
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.



**TO-220**  
FDP Series



**TO-220F**  
FQPF Series



## Absolute Maximum Ratings

Symbol	Parameter	FQP13N50CF	FQPF13N50CF	Unit
$V_{DSS}$	Drain-Source Voltage	500		V
$I_D$	Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )	13	13*	A
	- Continuous ( $T_C = 100^\circ\text{C}$ )	8	8*	A
$I_{DM}$	Drain Current - Pulsed	(Note 1)	52	A
$V_{GSS}$	Gate-Source voltage		$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	(Note 2)	530	mJ
$I_{AR}$	Avalanche Current	(Note 1)	13	A
$E_{AR}$	Repetitive Avalanche Energy	(Note 1)	19.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	4.5	V/ns
$P_D$	Power Dissipation ( $T_C = 25^\circ\text{C}$ )	195	48	W
	- Derate above $25^\circ\text{C}$	1.56	0.39	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range		-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds		300	$^\circ\text{C}$

\*Drain current limited by maximum junction temperature

## Thermal Characteristics

Symbol	Parameter	FQP13N50CF	FQPF13N50CF	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.64	2.58	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	$^\circ\text{C}/\text{W}$

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQP13N50CF	FQP13N50CF	TO-220	-	-	50
FQPF13N50CF	FQPF13N50CF	TO-220F	-	-	50

## Electrical Characteristics

$T_C = 25^\circ\text{C}$  unless otherwise noted

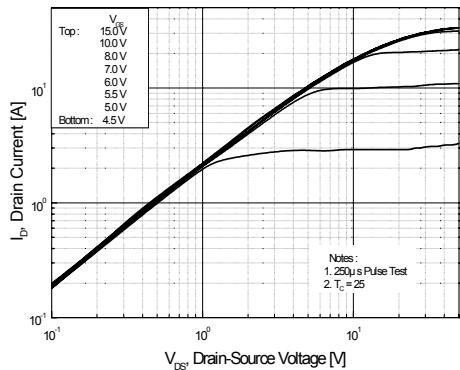
Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}$ , $I_D = 250\mu\text{A}$ , $T_J = 25^\circ\text{C}$	500	--	--	V
$\Delta BV_{DSS} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	0.5	--	$\text{V}/^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 500\text{V}$ , $V_{GS} = 0\text{V}$	--	--	10	$\mu\text{A}$
		$V_{DS} = 400\text{V}$ , $T_C = 125^\circ\text{C}$	--	--	100	$\mu\text{A}$
$I_{GSSF}$	Gate-Body Leakage Current, Forward	$V_{GS} = 30\text{V}$ , $V_{DS} = 0\text{V}$	--	--	100	nA
$I_{GSSR}$	Gate-Body Leakage Current, Reverse	$V_{GS} = -30\text{V}$ , $V_{DS} = 0\text{V}$	--	--	-100	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250\mu\text{A}$	2.0	--	4.0	V
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = 10\text{V}$ , $I_D = 6.5\text{A}$	--	0.43	0.54	$\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 40\text{V}$ , $I_D = 6.5\text{A}$	(Note 4)		15	--
<b>Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = 25\text{V}$ , $V_{GS} = 0\text{V}$ , $f = 1.0\text{MHz}$	--	1580	2055	pF
$C_{oss}$	Output Capacitance		--	180	235	pF
$C_{rss}$	Reverse Transfer Capacitance		--	20	25	pF
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 250\text{V}$ , $I_D = 13\text{A}$ $R_G = 25\Omega$	--	25	60	ns
$t_r$	Turn-On Rise Time		--	100	210	ns
$t_{d(off)}$	Turn-Off Delay Time		--	130	270	ns
$t_f$	Turn-Off Fall Time		--	100	210	ns
$Q_g$	Total Gate Charge	$V_{DS} = 400\text{V}$ , $I_D = 13\text{A}$ $V_{GS} = 10\text{V}$	--	43	56	nC
$Q_{gs}$	Gate-Source Charge		--	7.5	--	nC
$Q_{gd}$	Gate-Drain Charge		--	18.5	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current	--	--	13	--	A
$I_{SM}$	Maximum Pulsed Drain-Source Diode Forward Current	--	--	52	--	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{V}$ , $I_S = 13\text{A}$	--	--	1.4	V
$t_{rr}$	Reverse Recovery Time	$V_{GS} = 0\text{V}$ , $I_S = 13\text{A}$ $dI_F/dt = 100\text{A}/\mu\text{s}$	--	100	160	ns
$Q_{rr}$	Reverse Recovery Charge		--	0.35	--	$\mu\text{C}$

### Notes:

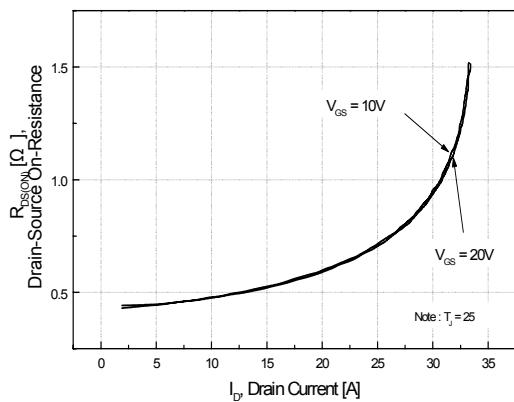
1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $L = 5.6\text{mH}$ ,  $I_{AS} = 13\text{A}$ ,  $V_{DD} = 50\text{V}$ ,  $R_G = 25\Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq 13\text{A}$ ,  $di/dt \leq 200\text{A}/\mu\text{s}$ ,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test: Pulse width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$
5. Essentially Independent of Operating Temperature Typical Characteristics

## Typical Performance Characteristics

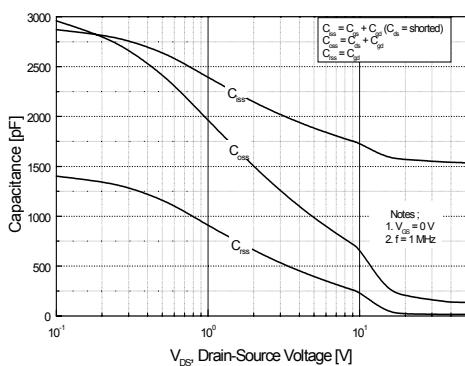
**Figure 1. On-Region Characteristics**



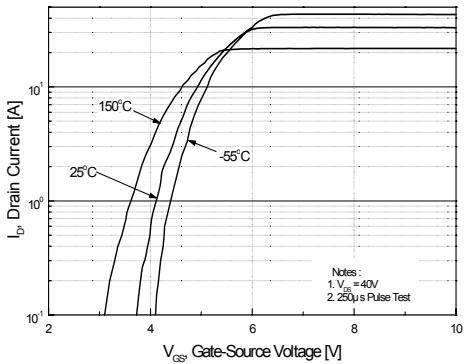
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



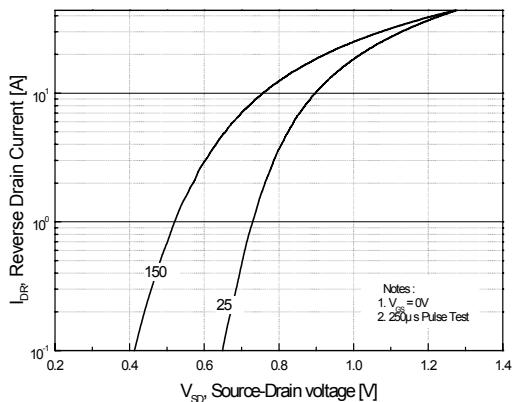
**Figure 5. Capacitance Characteristics**



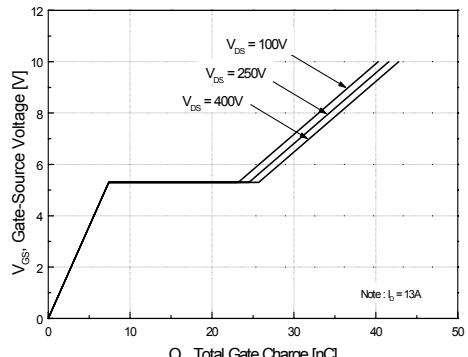
**Figure 2. Transfer Characteristics**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

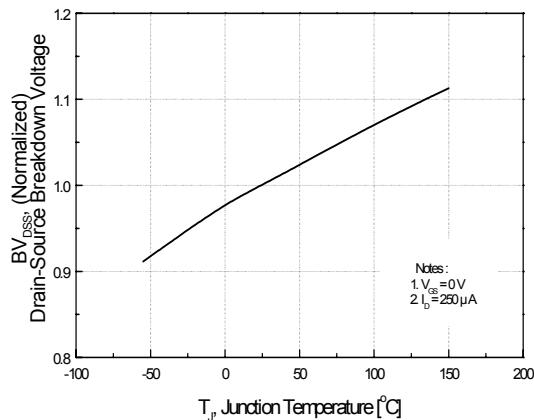


**Figure 6. Gate Charge Characteristics**

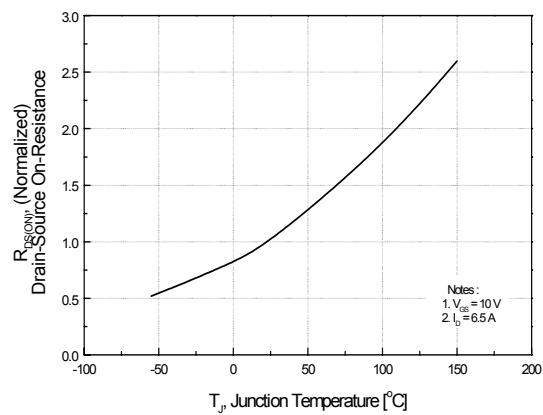


## Typical Performance Characteristics (Continued)

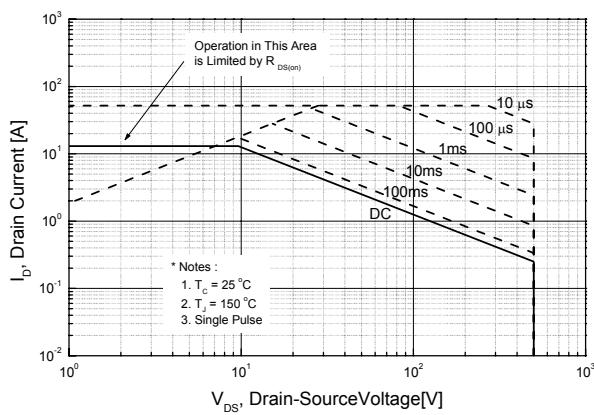
**Figure 7. Breakdown Voltage Variation vs. Temperature**



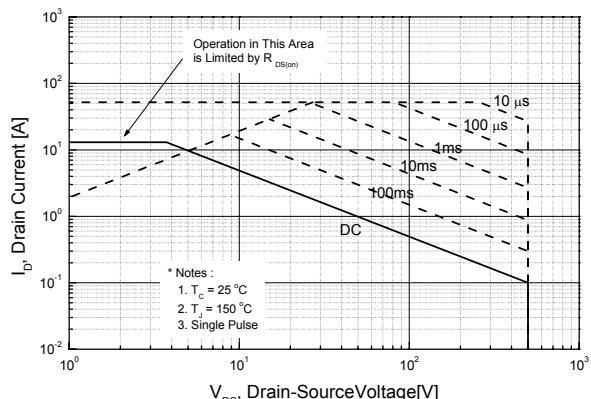
**Figure 8. On-Resistance Variation vs. Temperature**



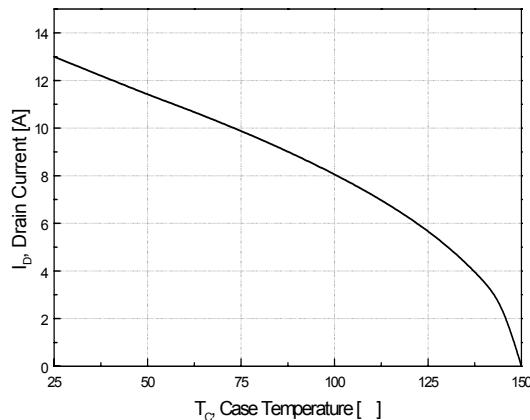
**Figure 9-1. Maximum Safe Operating Area for FQP13N50CF**



**Figure 9-2. Maximum Safe Operating Area for FQPF13N50CF**

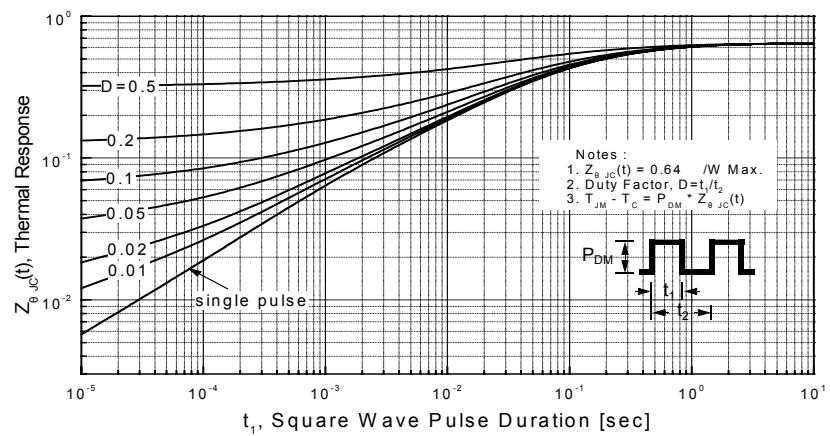


**Figure 10. Maximum Drain Current vs. Case Temperature**

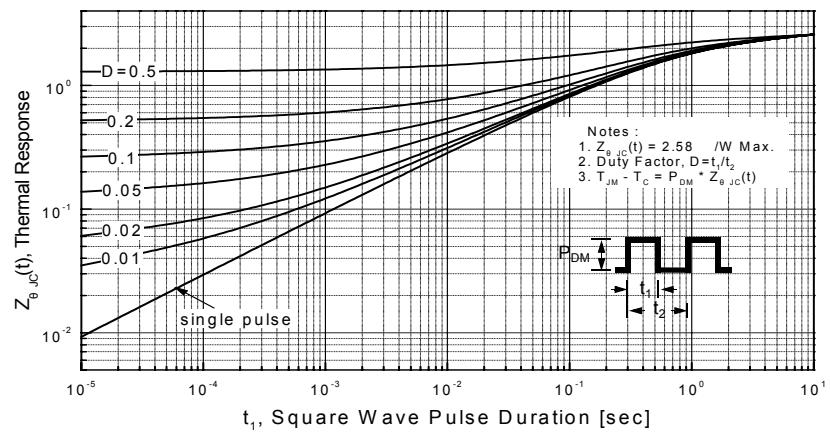


## Typical Performance Characteristics (Continued)

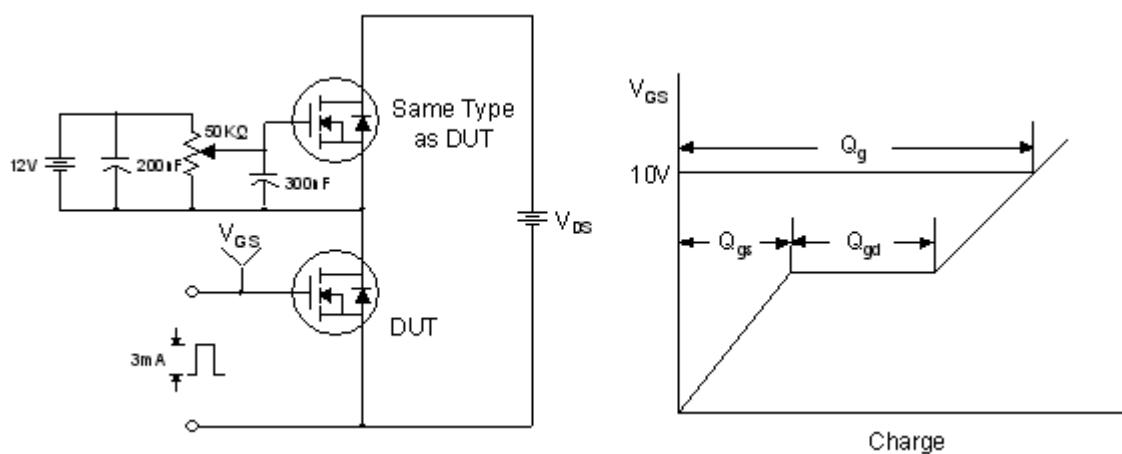
**Figure 11-1. Transient Thermal Response Curve for FQP13N50CF**



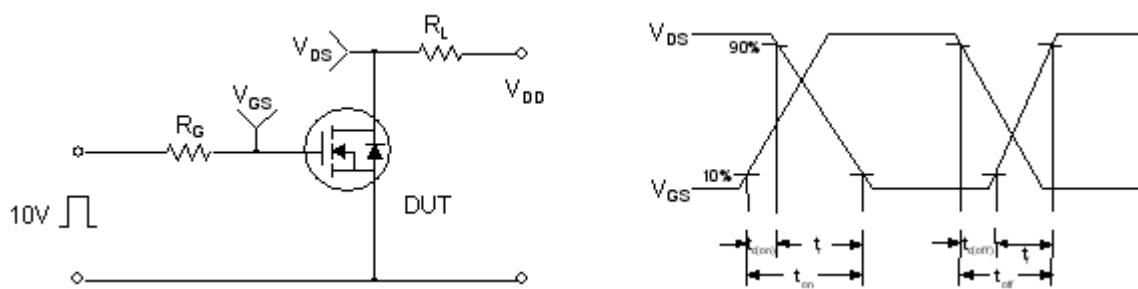
**Figure 11-2. Transient Thermal Response Curve for FQPF13N50CF**



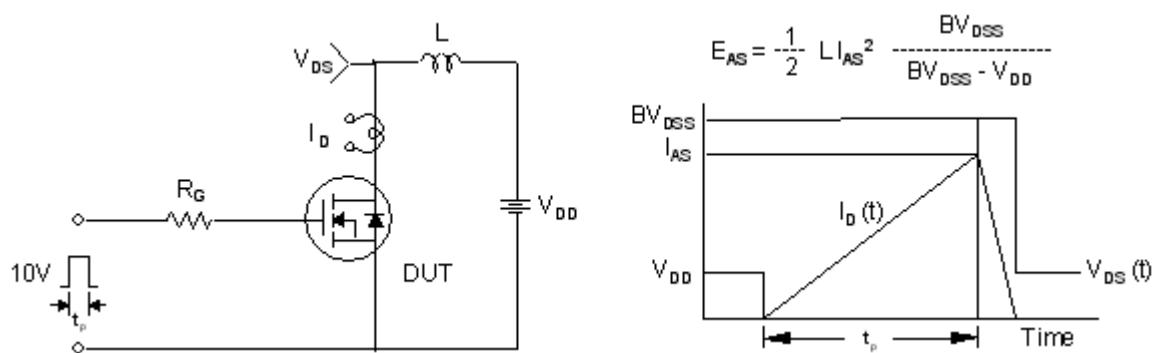
### Gate Charge Test Circuit & Waveform



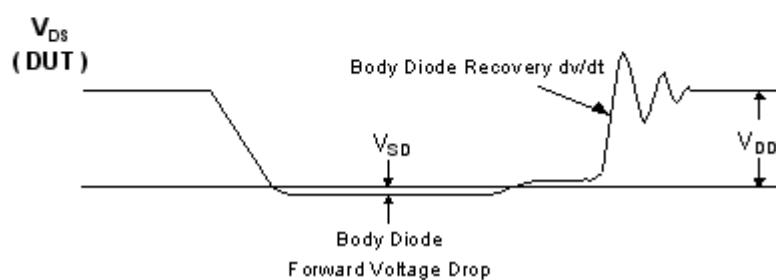
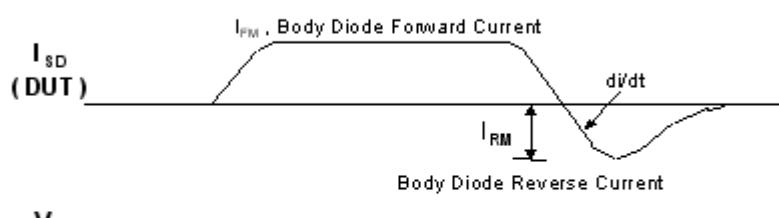
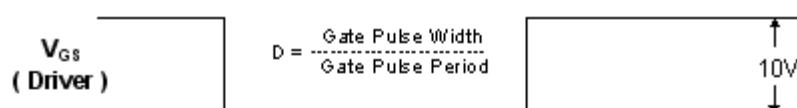
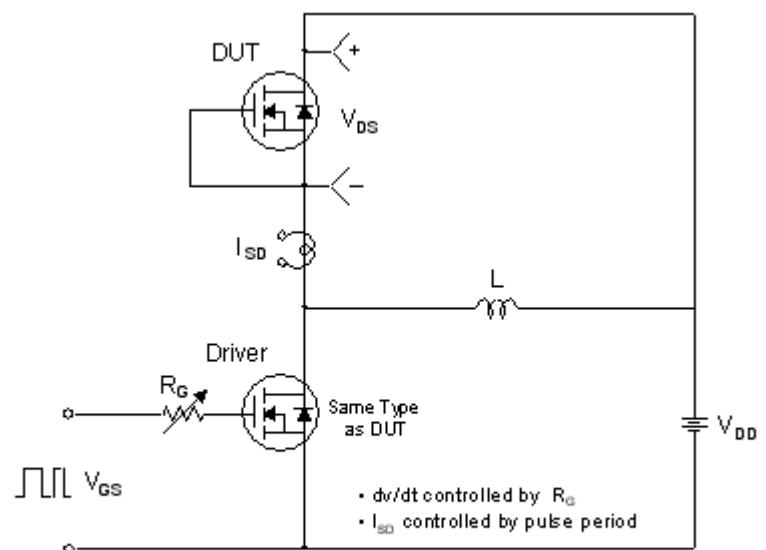
### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms

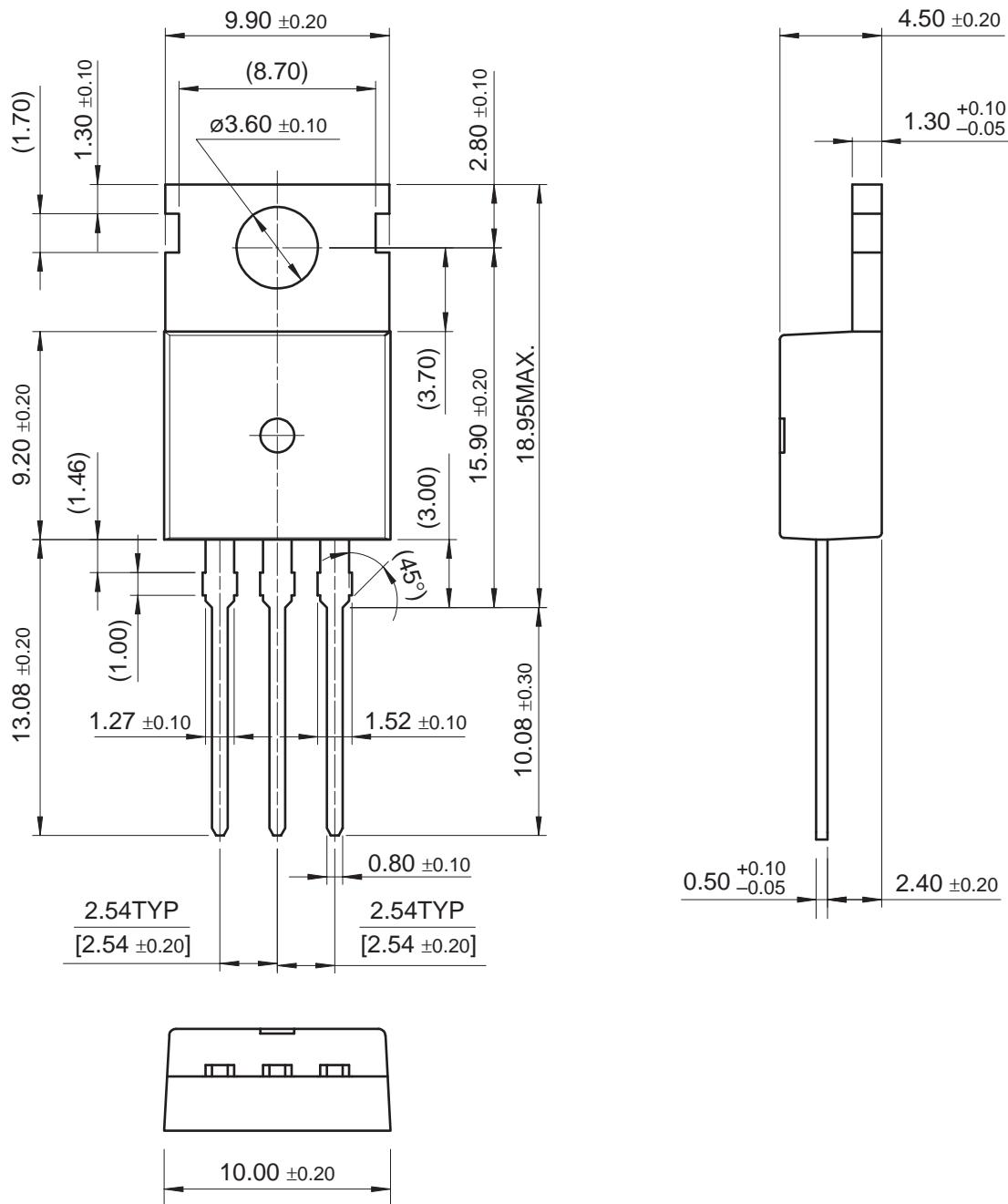


Peak Diode Recovery dv/dt Test Circuit & Waveforms

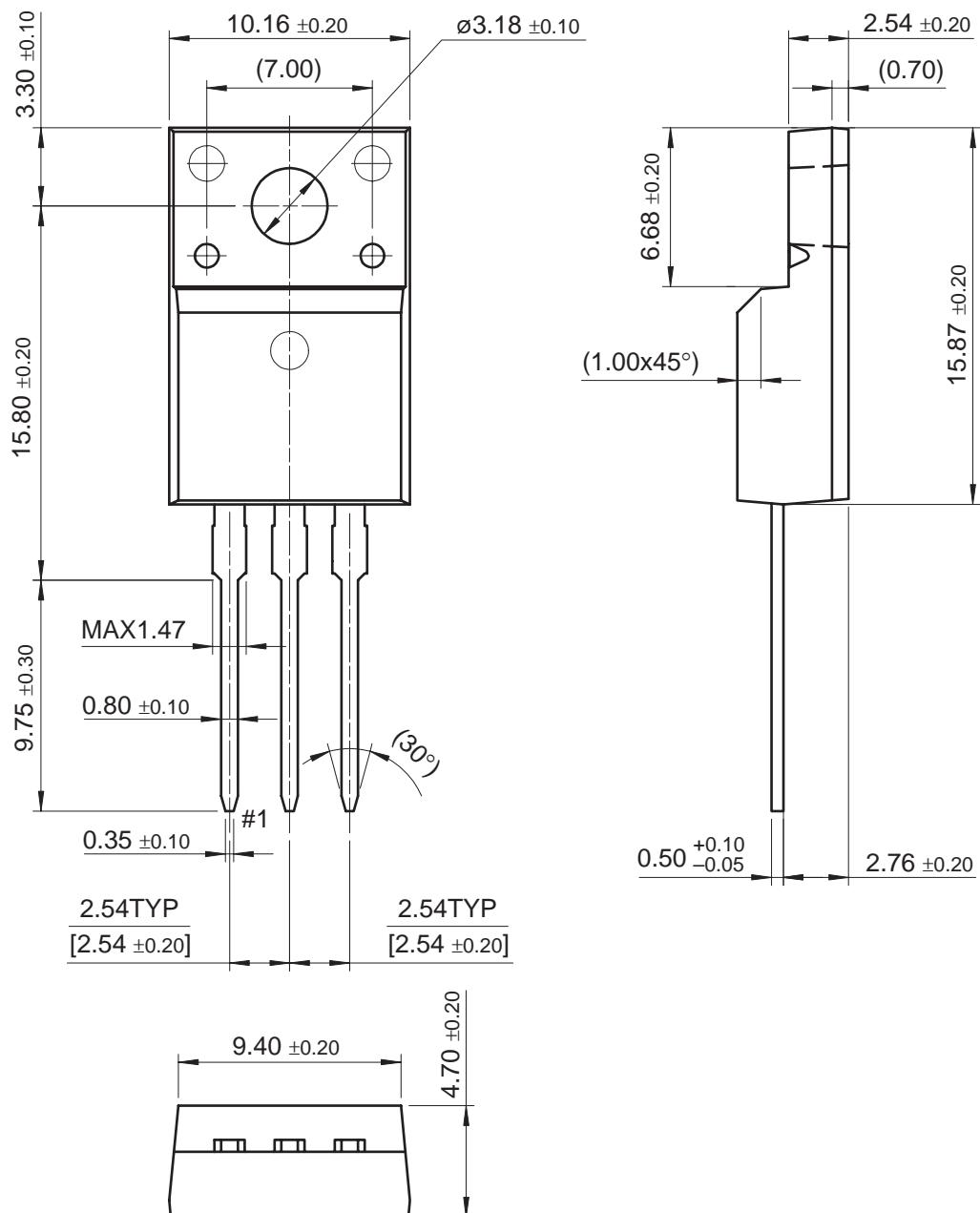


## Mechanical Dimensions

# TO-220



### Dimensions in Millimeters

**Mechanical Dimensions** (Continued)**TO-220F**

Dimensions in Millimeters

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EcoSPARK™	I <sup>2</sup> C™	MSXPro™	RapidConfigure™	TINYOPTO™
E <sup>2</sup> CMOS™	i-Lo™	OCX™	RapidConnect™	TruTranslation™
EnSigna™	ImpliedDisconnect™	OCXPro™	μSerDes™	UHC™
FACT™	IntelliMAX™	OPTOLOGIC®	ScalarPump™	UniFET™
FACT Quiet Series™		OPTOPLANAR™	SILENT SWITCHER®	UltraFET®
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Rev. I19